

LEEDS

FORENSIC SYSTEMS

TRACE-Z

TRACE EVIDENCE COMPARISON MICROSCOPE

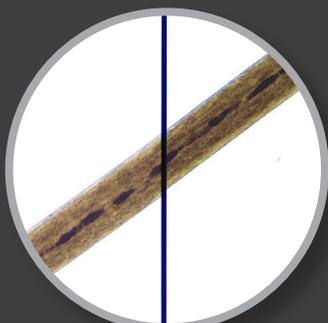
Introducing the Trace-Z, a powerful trace evidence comparison microscope encompassing Zeiss optical components. Leeds is pleased to add this newest microscope to our line of Zeiss-based forensic microscopes including the Discovery-Z firearms comparison microscope and the N-IRC stereo microscope camera/software kit. The Trace-Z is designed for forensic science and other applications which require side-by-side comparison of various specimens.

The Trace-Z, incorporating world-class optics, offers a unique, 23mm field of view, the largest field of view in the forensic marketplace. The system provides superior color and intensity balance requiring no adjustment by the operator. Providing an erect, unreversed image, the Trace-Z allows the operator the ability to quickly and easily manipulate specimens for examination. A motorized, sweeping mask adjuster allows the examiner to single-handedly control the image dividing line and overlay.

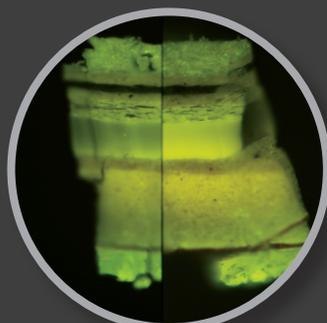
The Trace-Z, provides a variety of configurations to meet numerous application needs. Thus, the Trace-Z can be configured for brightfield, darkfield, polarized light, phase contrast, fluorescence, and other contrast methods. An optional dual-view version of the Trace-Z is available for simultaneous observation of evidence and is ideal for training and peer review.



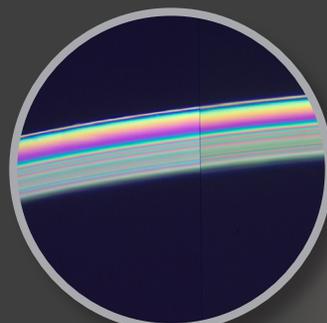
To learn more about the Trace-Z, please visit our website, www.leedsforensics.com, call (763) 546-8575 or e-mail our sales staff at sales@leedsmicro.com.



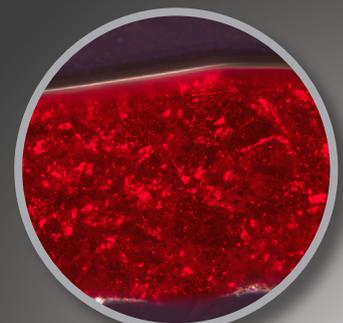
Brightfield image



Fluorescent light image



Polarized light image



Polarized light image

TRACE-Z

FEATURES

- 23 mm Field Number
- Erect unreversed image
- Color and intensity balanced
- Image Views: Split-field, superimposed, and individual right/left
- Integrated camera port with a fixed 70/30% split between eye pieces and camera
- NIST traceable, ISO/IEC 17025:2005 accredited, Certificate of Magnification Match
- Optional dual-view comparison microscope version available, with an illuminated LED arrow to aid in indicating specimen features



TECHNIQUES

- Brightfield (BF)
- Polarized Light (POL)
- Fluorescence
- Darkfield (DF)
- Phase Contrast
- Differential Interference Contrast (DIC)
- Reflected Brightfield/Darkfield/Polarized



TECHNICAL REQUIREMENTS

- Footprint of Trace-Z: 23" wide x 20" deep
- Height from table surface to eye point: From 18" - 23.5"
- Length between optical centers: 13.5"
- Optional Table Dimensions: 25-50" H x 35.5" W x 26" D
- Electrical Requirements: 120 - 240 VAC, 50 - 60 Hz

